



PATENT

THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/791,629
Filing Date: March 3, 2004
Applicant: Soo-Chan LEE et al.
Group Art Unit: 2829
Examiner: Jermele M. Hollington
Title: SYSTEM AND METHOD FOR TESTING SEMICONDUCTOR DEVICES
Attorney Docket: 2421-000033/US

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Randolph Building
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Alexandria, VA 22314
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April 27, 2007

**REQUEST FOR CONTINUED EXAMINATION
AND AMENDMENT UNDER 37 C.F.R. § 1.114**

Sir:

In response to the Final Office Action mailed December 27, 2006, the due date having been extended one (1) month, the following amendments and remarks are respectfully submitted in connection with the above-identified application.

Listing of the Claims begin on page 2 of this Amendment.

Remarks begin on page 16 of this Amendment.

	Claims remaining after Amendment		Highest number previously paid for		Present extra
Total	40	-	42	=	0
Independent	13	-	13	=	0

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